

DEC-20-2002 16:08

ELLS ST JOHN PS

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
H0001468

5098383424

P. 03/17

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Honeywell International Inc.PILING DATE
October 24, 2000GROUP
1753

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
Gm	AA	2,949,357	08/1960	Renick	148	421	
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
gm	AM	JP1092338	04/1969	Japan				
	AN	GB 810533	03/1959	Great Britain				
	AO	JP57019372	02/1982	Japan				
	AP	JP200273623	10/2000	Japan				
	AQ	SU1582043	09/1996	SU				

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AR					
	AS					
	AT					

EXAMINER

Hobayn A. Donald

DATE CONSIDERED

*1-14-03**EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered.
Include copy of this form with next communication to applicant.

Form PTO-1449
SC108
DEC 20 2002

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT <small>(Use several sheets if necessary)</small>					ATTY. DOCKET NO. H0001468		SERIAL NO. 09/695,814		
					APPLICANT Honeywell International Inc.				
					FILING DATE October 24, 2000		GROUP 1753		
U.S. PATENT DOCUMENTS									
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
mr	AA	5,939,788	08/1999	McTeer	0	257	751		
mr	AB	4,903,117	02/1990	Okamoto et al.	0	257	751		
	AC								
	AD								
	AE								
	AF								
	AG								
	AH								
	AI								
	AJ								
	AK								
	AL								
FOREIGN PATENT DOCUMENTS									
		Document Number	Date	Country	Class	Subclass	Translation		
mr	AM	WO 00/13235	09/03/2000	PCT	0		Yes	No	
	AN	08120445	14/05/1996	Japan	0				
	AO	FR 2 585 730 A1	08/01/1985	France	A				
	AP	GB 2 202 237 A	21/09/1988	GB	B				
mr	AQ	11074348	16/03/1999	Japan	0				
	AR	2000012539	14/01/2000	Japan	0				
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)									
mr	AS		Knotek et al., "The Structure and Composition of Ti-Zr-N, Ti-Al-Zr-N and Ti-Al-V-N Coatings" Materials Science and Engineering, A105/106, December 1988, pgs. 481-488.						
mr	AT		Sakamoto et al., "Preparation and Microstructure of Reactively Sputtered Ti _x Zr _y N Films" Thin Solid Films 228, May 1993, pgs. 169-172.						
	AU								
EXAMINER <i>Padley or Donald</i>				DATE CONSIDERED <i>1-14-03</i>					
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									

EV182655985

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Stephen P. Turner et al.FILING DATE
October 24, 2000GROUP
1753

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>Thru</i>	AA	5,171,379	12/1992	Kumar et al.	148	472	
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<i>Thru</i>	AM	252,442	09.06.1960	Australia				
<i>Thru</i>	AN	55-179784	12/1980	Japan				
	AO							
	AP							
	AQ							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

<i>Thru</i>	AR		Hughes et al., "Grain Subdivision and the Development of Local Orientations in Rolled Tantalum" Tantalum. The Minerals. Metals & Materials Society, 1996. pgs. 257-262. (Year is sufficiently early so that the month is not an issue.)
	AS		Arlt, Jr., "Sulfonation and Sulfonation to Thorium and Thorium Compounds" Kirk-Othmer Encyclopedia of chemical Technology vol. 22. pp. 541-564. (1993. Year is sufficiently early so that the month is not an issue.)
<i>Thru</i>	AT		Kirkbride et al., "The Effect of Yttrium on the Recrystallization and Grain Growth of Tantalum", J. Less-Common Metals. vol. 9. pp. 393-408. 1965. (Year is sufficiently early so that the month is not an issue.)

EXAMINER: *Anthony P. Donald*

DATE CONSIDERED

1-14-03

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Stephen P. Turner et al.FILING DATE
October 24, 2000GROUP
1753

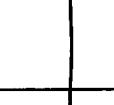
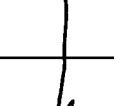
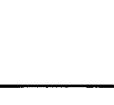
U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						

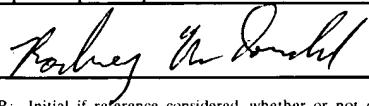
FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation
							Yes
	AB						No

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AC		National Research Corporation Press Release, pgs. 1-4, July 1964.	↓
	AD		National Research Corporation Data Sheet "SGS Tantalum", pgs. 1-7, no date.	↓
	AD		ASTM Standard Specification for Tantalum and Tantalum Alloy Plate, Sheet, and Strip, pgs. 558-561, 1992. (Year is sufficiently early so that the month is not an issue.)	↓
	AE		Kumar, et al. "Effect of Intermetallic Compounds of the Properties of Tantalum" Materials Research Society Symposium Proceedings, vol. 322, pgs. 413-422, 1994. (Year is sufficiently early so that the month is not an issue.)	↓
	AF		Kumar, et al. "Effect of Intermetallic Compounds of the Properties of Tantalum" Refractory Metals & Hard Materials, vol. 12, pgs. 35-40, 1994. (Year is sufficiently early so that the month is not an issue.)	↓
	AG		Klein et al., "Inhomogeneous Textures in Tantalum Sheets" Materials Science Forum, vol. 157-162, pgs. 1423, (1994). (Year is sufficiently early so that the month is not an issue.)	↓
	AH		Clark et al., "Influence of Transverse Rolling on the Microstructural and Texture Development in Pure Tantalum", Metallurgical Transactions, vol. 23A, pgs. 2183-2191, August 1992.	↓
	AI		Raabe, et al., "Texture and Microstructure of Rolled and Annealed Tantalum", Materials Science and Technology, Vol. 10, pgs. 299-305, April 1994.	↓
	AJ		Wright et al., "Texture Gradient Effects in Tantalum", International Conference on Textures of Materials, 7 pgs., September 1993.	↓
	AK		Wright et al., "Textural and Microstructural Gradient Effects on the Mechanical Behavior of a Tantalum Plate", Metallurgical Transactions A, 25A (1994), pgs. 1-17. (Year is sufficiently early so that the month is not an issue.)	↓
	AL		Clark et al., "Effect of Processing Variables on Texture and Texture Gradients in Tantalum", Metallurgical Transactions A, Vol. 22A, September 1991, pgs. 2039-2047.	↓
	AM		Kumar et al., "Corrosion Resistant Properties of Tantalum" Corrosion 95, Paper No. 253, 14 pages. (No date)	↓
	AN			
	AO			
	AP			

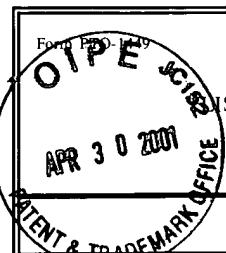
EXAMINER



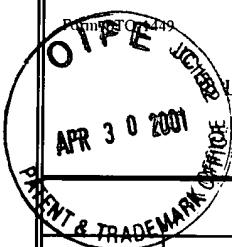
DATE CONSIDERED

1-14-03

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

 LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. H0001468 (HO58-044)	SERIAL NO. 09/695,814	
					APPLICANT Honeywell International, Inc. (Pennsylvania)		
					FILING DATE October 24, 2000	GROUP Unassigned	
					U.S. PATENT DOCUMENTS		
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>lyn</i>	AA	6,024,847	02/15/00	Rosenberg et al.	304	243.1	<i>RECEIVED</i> <i>MAY 2 2001</i>
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes
							No
	AL						
	AM						
	AN						
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
	AT						
EXAMINER <i>Tobey M. Donald</i>		DATE CONSIDERED <i>1-14-03</i>					

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
H0001468 (H058-044)SERIAL NO.
09/695,814

LIST OF ART CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT
Honeywell International, Inc. (Pennsylvania)FILING DATE
October 24, 2000GROUP
Unassigned

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>Y</i>	AA	60/225,518 (Serial No.) As filed and amended		Jianxing Li et al.			08/15/00
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

RECEIVED
 MAY 2 2001
TC 1700

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AR							
	AS							
	AT							

EXAMINER:

Kathy Mc Dowell

DATE CONSIDERED

1-14-03

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.